



SEM Supporter



【SEM Support Software】

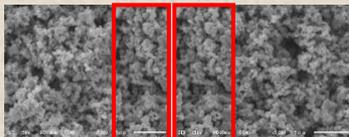
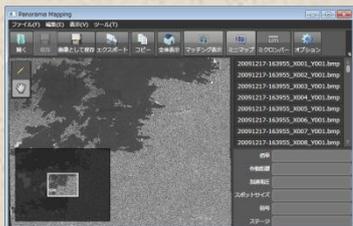
Corresponding model:
JEOL: FE-SEM (JSM-7000 Series)
JEOL: W-SEM (MP Series)



By SYSTEM IN FRONTIER INC.

『Montage』

- The SEM image of high magnification is photoed with a tile. It is displayed by montage.
- The image is photoed by overlap. A position gap is calculated and rectified by overlap.



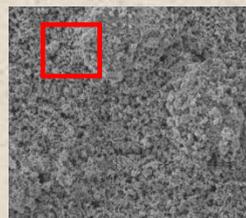
《View》

- A montage image is saved at a file.
- A micron bar is displayed.
- A position on display is checked on a mini map.



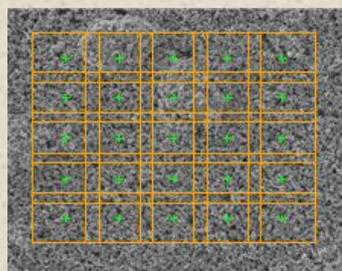
《Review Support》

- A high magnification image can be displayed from a montage image.
- A stage is movable to the position which photoed the image.

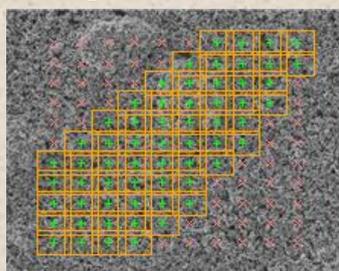


Mag	x 5,000
WD	10 mm
Acc Vol	15 kV
SS	40
Signal	SEI
ViewCenter	{X=10.481, Y=-15.186}
ViewRect	{X=10.4682, Y=-15.1956, W}

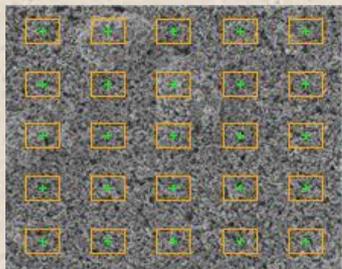
【Tile】



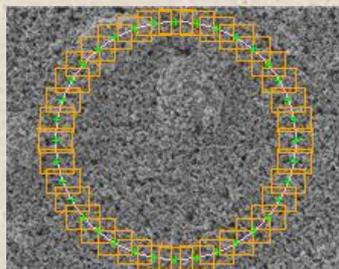
【Skip】



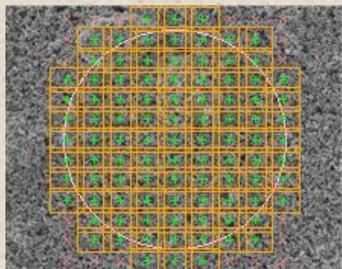
【Grid】



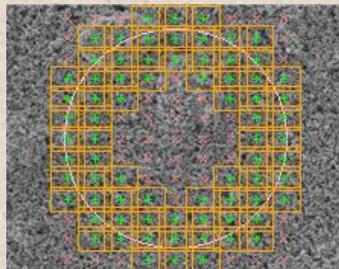
【Ring】



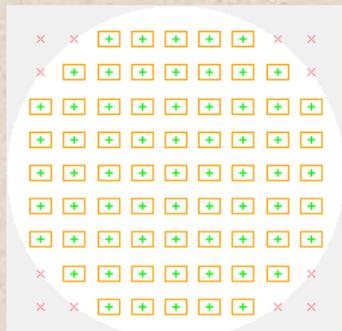
【Circle】



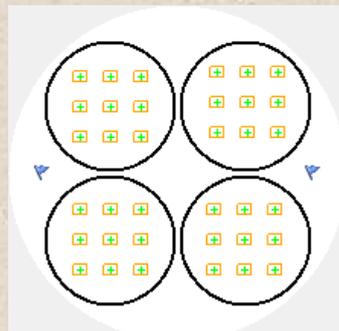
【Doughnut】



【Single Holder】

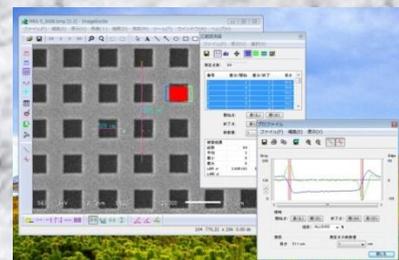


【Multi Holder】



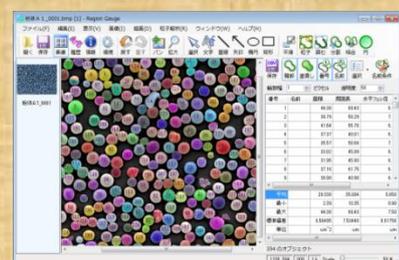
『Continuous photography with measurement』 ※option

- If the software to measure is used together, it can measure taking a photograph.
- The position to measure is customizable.



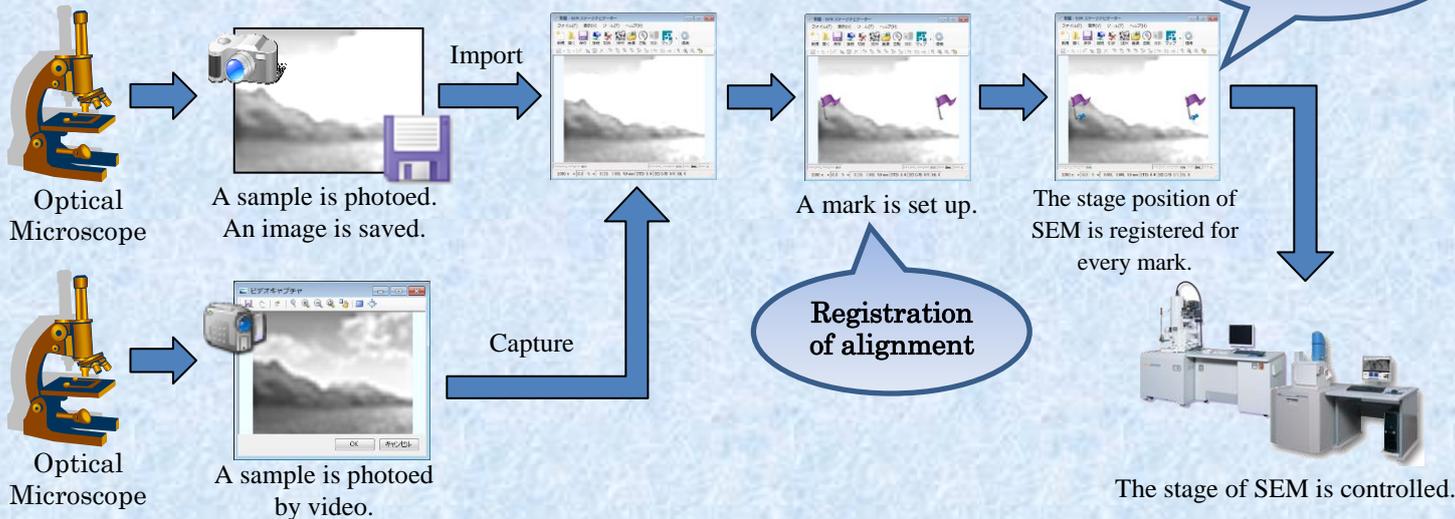
『Continuous photography with particle analysis』 ※option

- If the software to particle analysis is used together, it can measure taking a photograph.
- An analysis result can be saved.

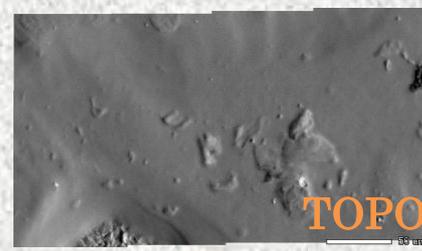
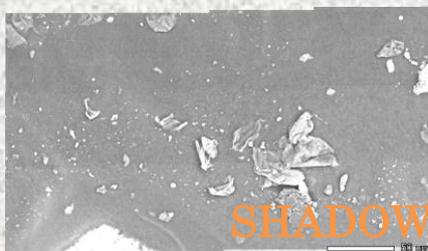


『OM LINK』

The stage of SEM is movable, referring to the image of an optical microscope.

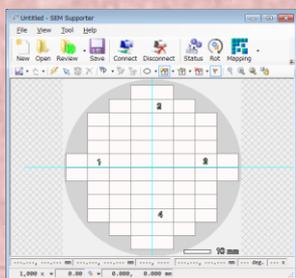


『Multi-Signal Photography』 ※MP series



『Wafer fixed point observation』

- An observation position can be registered for every chip.
- A viewpoint is photoed continuously.
- If it exchanges samples, a photography position is re-calculated by an alignment function.



『for 150mm Sample』 ※MP series

- The movable range of a stage is classified by color and

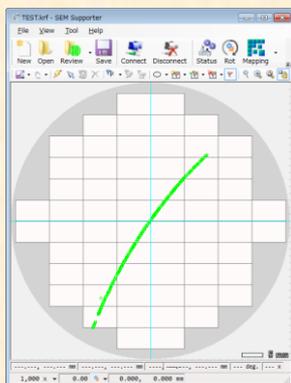


『Inspection result review』 ※option

- The output file of an inspection machine is loaded.
- * Custom-made is possible (consultation required).

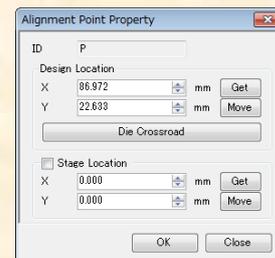
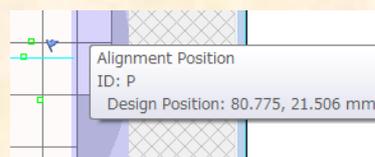
ID	Variable	XINDEX	YINDEX	CLASSNUMBER	RC
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6	✓	0	-4	0	0
7	✓	0	-4	0	0
8	✓	0	-4	0	0
9	✓	0	-4	0	0
10	✓	0	-4	0	0

ID: 5 Total: 334 Close



《Alignment》

- A viewpoint is smoothly movable by registration and setup of alignment.
- An offset position can be registered for every viewpoint.



Specifications, design and terms of offers may change without notice.

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